Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/813,782	MITA, KIYOSHI
Examiner	. Art Unit
Chris C. Chu	2815

SEARCHED						
Class	Subclass	Date	Examiner			
257	E21.505, 678, 774 and 772	4/6/2007	C.C.			
			00			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	4/6/2007	C.C.		